

## STF35N65DM2

## N-channel 650 V, 0.093 Ω typ., 32 A MDmesh™ DM2 Power MOSFET in a TO-220FP package

Datasheet - production data

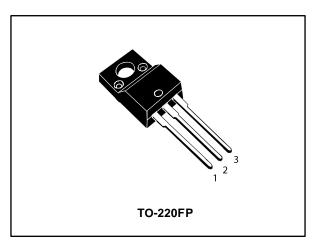
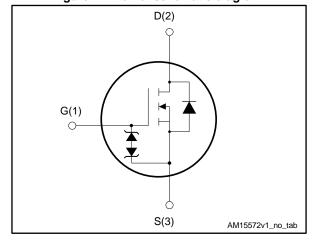


Figure 1: Internal schematic diagram



### **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	ΙD	Ртот
STF35N65DM2	650 V	0.110 Ω	32 A	40 W

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- Low on-resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

### **Applications**

Switching applications

### **Description**

This high voltage N-channel Power MOSFET is part of the MDmesh  $^{\text{TM}}$  DM2 fast recovery diode series. It offers very low recovery charge (Q<sub>rr</sub>) and time (t<sub>rr</sub>) combined with low R<sub>DS(on)</sub>, rendering it suitable for the most demanding high efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

**Table 1: Device summary** 

Order code	Marking	Package	Packing
STF35N65DM2	35N65DM2	TO-220FP	Tube

Contents STF35N65DM2

## Contents

1	Electric	cal ratings	3
2	Electric	cal characteristics	4
	2.1	Electrical characteristics (curves)	6
3	Test cir	·cuits	8
4	Packag	e information	9
	4.1	TO-220FP package information	10
5	Revisio	on history	12

STF35N65DM2 Electrical ratings

# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit	
V <sub>G</sub> s	Gate-source voltage	±25	V	
1_	Drain current (continuous) at T <sub>case</sub> = 25 °C		_	
ID	Drain current (continuous) at T <sub>case</sub> = 100 °C		Α	
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	90	Α	
P <sub>TOT</sub>	Total dissipation at T <sub>case</sub> = 25 °C	40	W	
dv/dt <sup>(2)</sup>	Peak diode recovery voltage slope	50	V/ns	
dv/dt <sup>(3)</sup>	MOSFET dv/dt ruggedness	50	V/IIS	
V <sub>ISO</sub>	Insulation withstand voltage (RMS) from all three leads to external heat-sink (t = 1 s; $T_c$ = 25 °C)	2.5	kV	
T <sub>stg</sub>	Storage temperature range	-55 to 150	)	
Tj	Operating junction temperature range		°C	

#### Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case	3.1	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient	62.5	C/VV

**Table 4: Avalanche characteristics** 

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or non-repetitive	4	Α
E <sub>AS</sub> <sup>(1)</sup>	Single pulse avalanche energy	1150	mJ

### Notes:

 $<sup>\</sup>ensuremath{^{(1)}}\mbox{Pulse}$  width is limited by safe operating area.

 $<sup>^{(2)}</sup>I_{SD} \leq 32$  A, di/dt=900 A/ $\mu s$ , VDs peak < V(BR)DSS, VDD = 80% V(BR)DSS

 $<sup>^{(3)}</sup>V_{DS} \le 520 \text{ V}$ 

 $<sup>^{(1)}</sup>Starting~T_j$  = 25 °C,  $I_D$  =  $I_{AR},~V_{DD}$  = 50 V.

Electrical characteristics STF35N65DM2

### 2 Electrical characteristics

(T<sub>case</sub> = 25 °C unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	650			V
	Zoro goto voltago droin	$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$			1	
IDSS	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V},$ $T_{case} = 125 \text{ °C}^{(1)}$			100	μΑ
Igss	Gate-body leakage current	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = ±25 V			±5	μΑ
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	3	4	5	V
R <sub>DS(on)</sub>	Static drain-source on- resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 16 A		0.093	0.110	Ω

#### Notes:

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		-	2540	ı	
Coss	Output capacitance	V <sub>DS</sub> = 100 V, f = 1 MHz,	-	115	ı	pF
C <sub>rss</sub>	Reverse transfer capacitance	$V_{GS} = 0 V$	-	2.5	-	Pi
Coss eq. (1)	Equivalent output capacitance	V <sub>DS</sub> = 0 to 520 V, V <sub>GS</sub> = 0 V	-	204	-	pF
Rg	Intrinsic gate resistance	f = 1 MHz, I <sub>D</sub> = 0 A	-	4.2	-	Ω
$Q_g$	Total gate charge	$V_{DD} = 520 \text{ V}, I_D = 32 \text{ A}, V_{GS} = 0$	-	56.3	-	
Qgs	Gate-source charge	to 10 V (see Figure 15: "Test	-	12.7	-	nC
Q <sub>gd</sub>	Gate-drain charge	circuit for gate charge behavior")	-	27.6	-	

### Notes:

**Table 7: Switching times** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	V <sub>DD</sub> = 325 V, I <sub>D</sub> = 16 A,	ı	23.4	•	
tr	Rise time	$R_G = 4.7 \Omega$ , $V_{GS} = 10 V$ (see Figure 14: "Test circuit for		23	ı	
t <sub>d(off)</sub>	Turn-off delay time	resistive load switching times"	-	72		ns
t <sub>f</sub>	Fall time	and Figure 19: "Switching time waveform")	-	10.4		



<sup>&</sup>lt;sup>(1)</sup>Defined by design, not subject to production test.

 $<sup>^{(1)}</sup>$ Coss eq. is defined as a constant equivalent capacitance giving the same charging time as Coss when VDs increases from 0 to 80% VDss.

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		32	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		90	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 32 A	-		1.6	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 32 A, di/dt = 100 A/μs,	-	100		ns
Qrr	Reverse recovery charge	V <sub>DD</sub> = 60 V (see Figure 16: "Test circuit for inductive load	-	0.42		μC
I <sub>RRM</sub>	Reverse recovery current	switching and diode recovery times")	-	8.4		Α
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 32 A, di/dt = 100 A/µs,	-	205		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150 ^{\circ}\text{C}$ (see Figure 16: "Test circuit for	-	1.8		μC
I <sub>RRM</sub>	Reverse recovery current	inductive load switching and diode recovery times")	-	17.6		Α

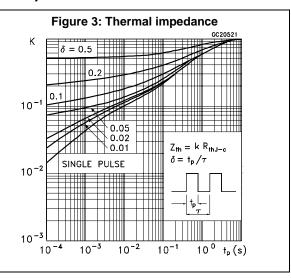
#### Notes:

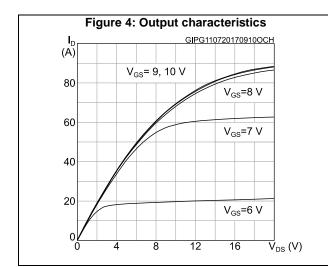
<sup>&</sup>lt;sup>(1)</sup>Pulse width is limited by safe operating area.

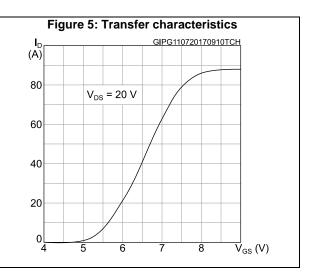
 $<sup>^{(2)}\</sup>text{Pulse}$  test: pulse duration = 300  $\mu\text{s},$  duty cycle 1.5%

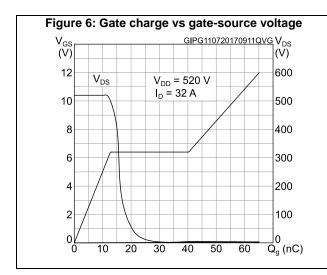
### 2.1 Electrical characteristics (curves)

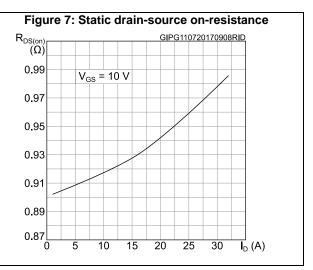
Figure 2: Safe operating area GADG061220171053SOA Operation in this area is limited by R<sub>DS(on)</sub> 10<sup>2</sup> t<sub>0</sub>=1 μs 10 t<sub>o</sub>=10 μs t<sub>p</sub>=100 μs t<sub>p</sub>=1 ms 10<sup>0</sup> T<sub>≤</sub>150 °C t<sub>o</sub>=10 ms T<sub>o</sub>= 25°C single pulse 10<sup>-1</sup> 10<sup>2</sup>  $\vec{V}_{DS}(V)$ 10° 10<sup>-1</sup> 10<sup>1</sup>





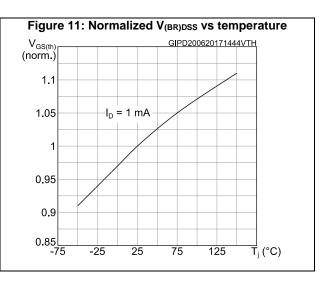


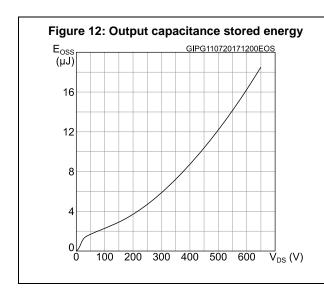


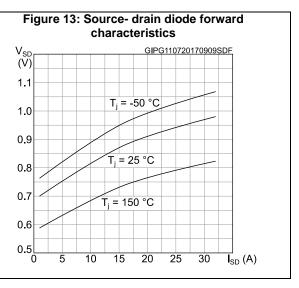


STF35N65DM2 Electrical characteristics

Figure 8: Capacitance variations GIPG110720170909CVR (pF)  $10^{4}$ C<sub>ISS</sub>  $10^{3}$ 10<sup>2</sup>  $C_{oss}$ 10<sup>1</sup> f = 1 MHz  $C_{RSS}$ 10<sup>0</sup> 10<sup>-1</sup> 10<sup>0</sup> 10<sup>1</sup> 10<sup>2</sup>  $\vec{V}_{DS}(V)$ 







Test circuits STF35N65DM2

### 3 Test circuits

Figure 14: Test circuit for resistive load switching times

Figure 15: Test circuit for gate charge behavior

12 V 47 KΩ 100 Ω D.U.T.

12 V 47 KΩ VGD

14 VGD

14 VGD

14 VGD

15 VGD

16 CONST 100 Ω OVG

17 VGD

18 VGD

18 VGD

18 VGD

18 VGD

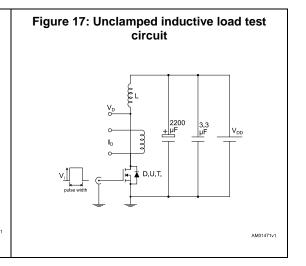
18 VGD

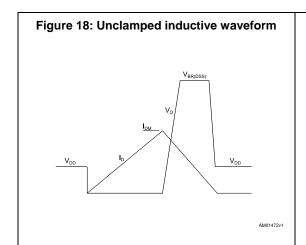
18 VGD

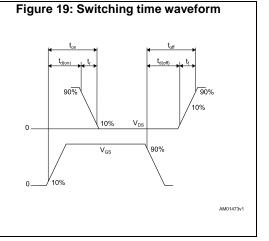
19 VGD

18 VGD

Figure 16: Test circuit for inductive load switching and diode recovery times







## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

# 4.1 TO-220FP package information

Figure 20: TO-220FP package outline

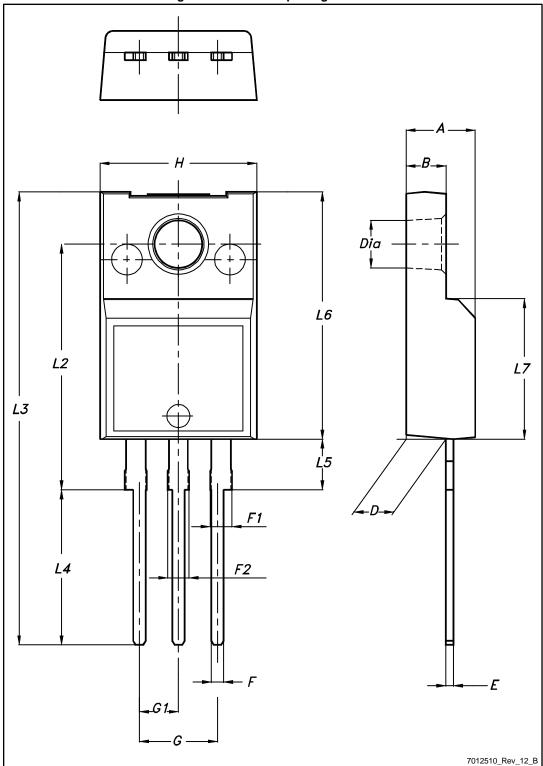


Table 9: TO-220FP package mechanical data

D.L.		mm	
Dim.	Min.	Тур.	Max.
A	4.4		4.6
В	2.5		2.7
D	2.5		2.75
E	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
Н	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

Revision history STF35N65DM2

## 5 Revision history

Table 10: Document revision history

Date	Revision	Changes
21-Jul-2017	1	Initial release
04-Dec-2017	2	Document status changed from preliminary to production data.  Updated Table 2: "Absolute maximum ratings" and Table 8: "Source-drain diode".  Updated Figure 2: "Safe operating area".  Minor text changes.

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